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INTRODUCTION TO SECONDARY ELECTRON DETECTION

In Partial Fulfillment of the CAMTEC Workshop

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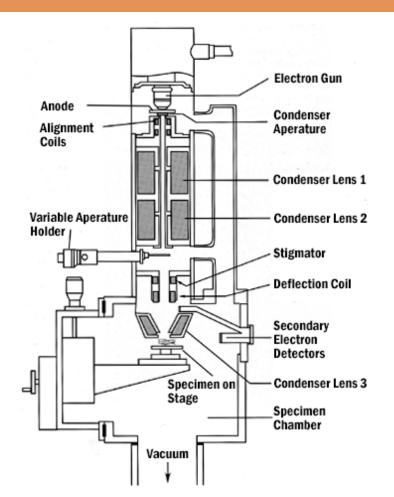
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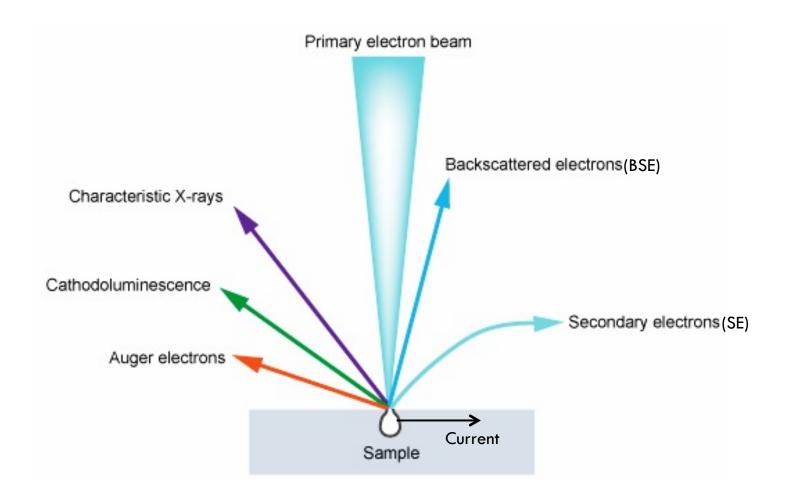
- Introduction
- Beam-Sample Interaction
- Secondary Electron
 - Imaging Features
 - Energy Range
 - Types
 - Yield
 - Detection

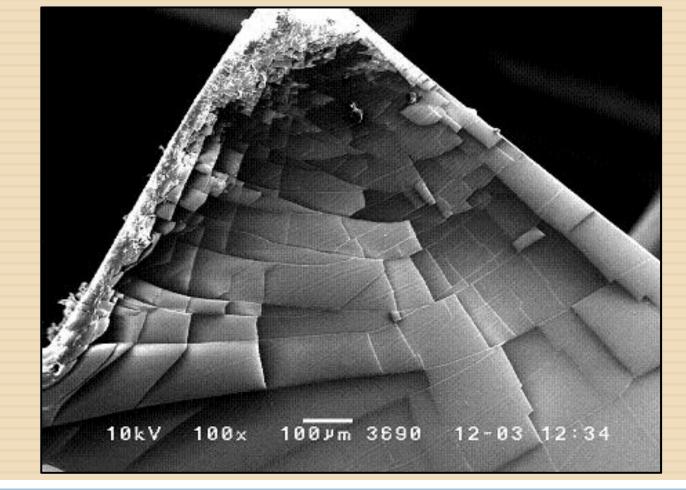
Introduction

Scanning Electron Microscope



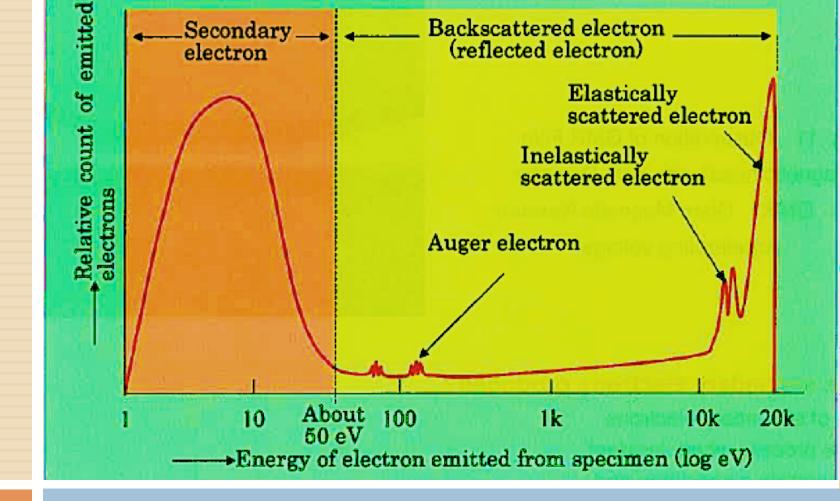
Beam-Sample Interaction





Secondary Electron: Imaging Features

- Produces High Field of Depth Image
- Intricate Topographical Imaging



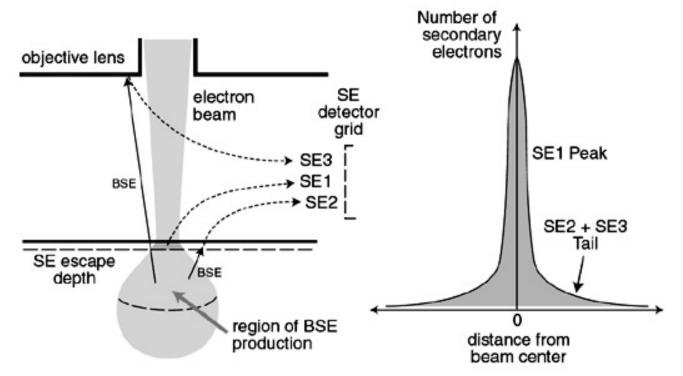
Secondary Electron: Energy Range

Secondary Electrons are given off at around 50eV.

However, Back Scattered Electrons require high electron energy.

Secondary Electron: Types

- SE1: Electron release from Incident Beam
- SE2: Electron release from Backscattered Output
- SE3: Electron release from BSE and chamber strike



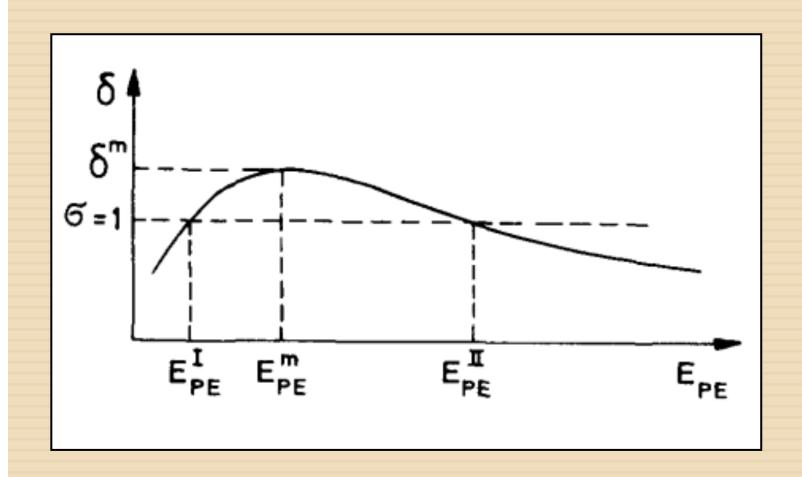
Secondary Electron: Yield

Definition

The amount of Secondary Electrons produced in relation to the amount of Primary Electron induced to a specimen.

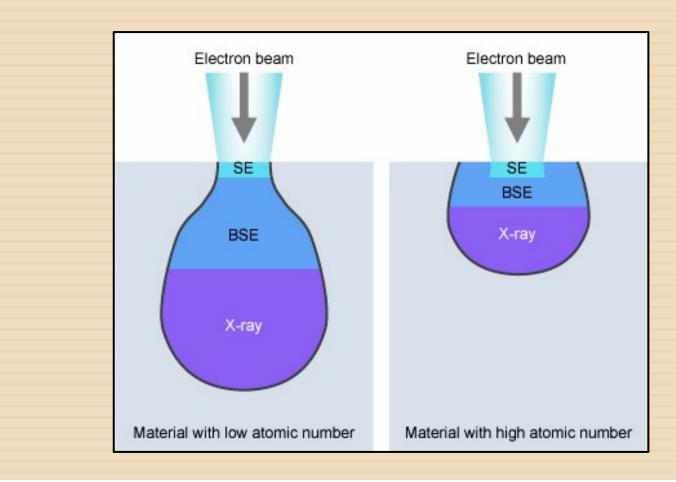
Subject To

- Surface Morphology
- □ Specimen Tilt: $(1/\cos\theta)$
- Material Atomic Number: Z



Secondary Electron: Yield

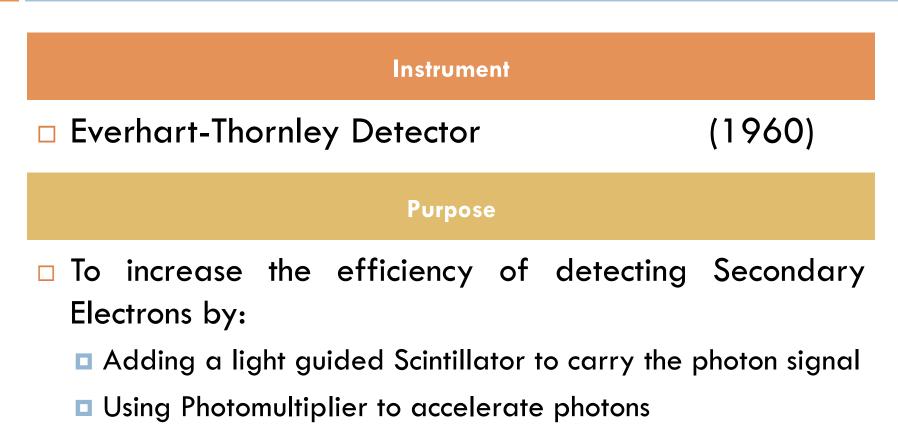
Highest Secondary Electron Yield at Optimal Primary Beam Energy



Secondary Electron: Yield

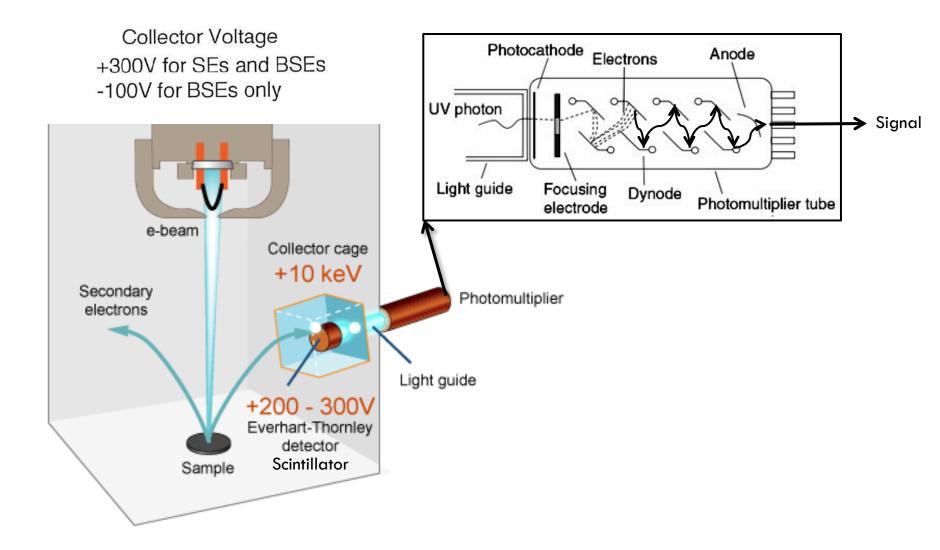
Atomic Number (Z) effect on Secondary Electron Yield

Secondary Electron: Detection



□ To improve Signal-Noise Ratio (SNR) for better imaging

Secondary Electron: Detection





Picture Mania: Ant (2mm) and Microchip









- Hitachi: Let's Familiarize Ourselves with the SEM
- Everhart, TE and RFM Thornley (1960).
 "Wide-band detector for micro-microampere low-energy electron currents"
- <u>http://www.ammrf.org.au/myscope/sem</u>